## **Electronic Supplementary Information**

Temperature Dependent of Photoluminescence Studies in ZnO Microrods by FZ Method

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Figure S1: Photograph of a commercial optical floating zone furnace (image furnace): model FZ-T-10000-H-VI-VP, CSI Japan.



Figure S2: The growth morphology image of the ZnO microrods observed in the FZ furnace.

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Figure S3: Temperature profile for four mirror used in the FZ furnace around the horizontal plane. The similar temperature profile can be found from the website:

http://www.crystalsys.co.jp/english/product02\_e.html or http://scidre.de/index.php?id=12.



Figure S4: Raman spectrum of the ZnO microrods at room temperature

As shown in S4, four peaks at 331, 383, 412 and 436 cm<sup>-1</sup> were observed. The peak at 436 cm<sup>-1</sup> is attributed to ZnO non-polar optical phonons of the  $E_2^{high}$  mode, the peak at 412 cm<sup>-1</sup>, 383 cm<sup>-1</sup> and 331 cm<sup>-1</sup> corresponds to  $E_1(TO)$ ,  $A_1(TO)$  and  $E_2^{high}-E_2^{low}$  symmetry, respectively.<sup>[1-3]</sup> The peak at 589 cm<sup>-1</sup> is related to local vibrational modes associated with intrinsic lattice defects.<sup>[3]</sup> This peak is weak in intensity which is consistent with the presence of low defect levels in the ZnO microrods.



Figure S5: (a) Room temperature PL spectra of as prepared ZnO microrods recorded at different excitation intensities from  $1 \text{ kW/cm}^2$  to  $100 \text{ kW/cm}^2$ . (b) Luminescence spectra as the as a function of excitation intensity is increased from power density.

S5(a) shows the evolution of the band edge at room temperature as the excitation intensity is increased from 1 kW/cm<sup>2</sup> to 100 kW/cm<sup>2</sup>. At low excitation intensities (1 kW/cm<sup>2</sup>), a visible green fluorescence emission at 2.35 eV (527 nm) was observed due to the presence of ZnO defects.<sup>[4, 5]</sup> As the excitation intensity reaches 2 kW/cm<sup>2</sup>, a second peak emerges at 3.145 eV (394 nm) which is due to the recombination of the free excitons of ZnO. At excitation intensities above 100 kW/cm<sup>2</sup>, the free excitons peak dominates at PL spectra, as shown in S 5(b).









S6 PL spectra at different temperatures

## Reference

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